

High Aspect Ratio 'Infinitely' Long Gold Gratings

Edward Chakmakian, C. L. Arrington, A. L. Young, A. E. Hollowell

Correspondence: aehollo@sandia.gov (505) 844-8301

Sandia National Laboratories, Albuquerque, NM 87123, USA

Electrochemical Deposition (ECD) offers unique capabilities for new device creation where traditional CMOS is unable to compare. Due to the nature of precise additive processing, as opposed to blanket material deposition, ECD is not hindered by line of sight constraints and keyhole effects inherent in traditional CMOS processes. Additionally, utilizing mold construction methods such as UV lithography, x-ray lithography, and Deep Reactive Ion Etching (DRIE), metal gratings can be realized at high aspect ratios for unique and complex device realization. In this work we've combined ECD with unique templates to realize high aspect ratio (as high as 50:1) gold gratings that up to 4 inches in length Metalmichromachining.sandia.gov

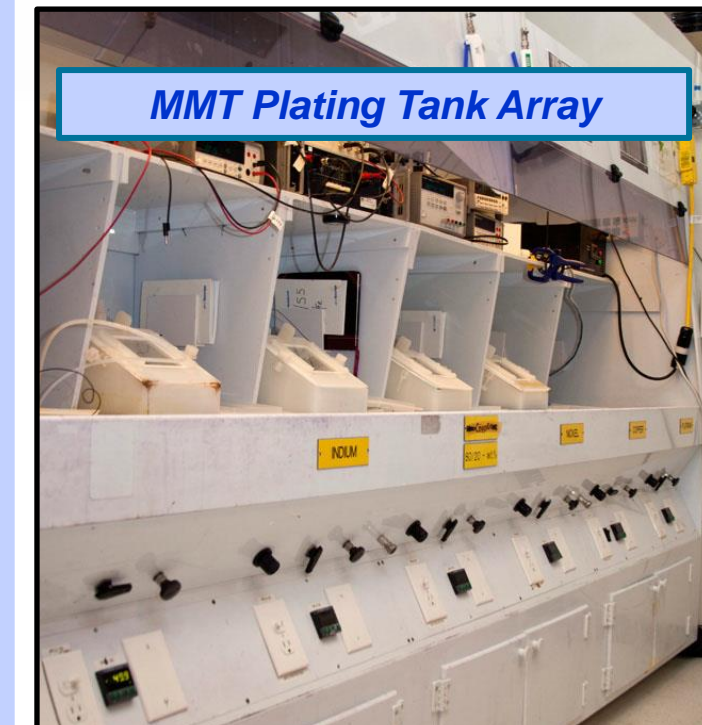
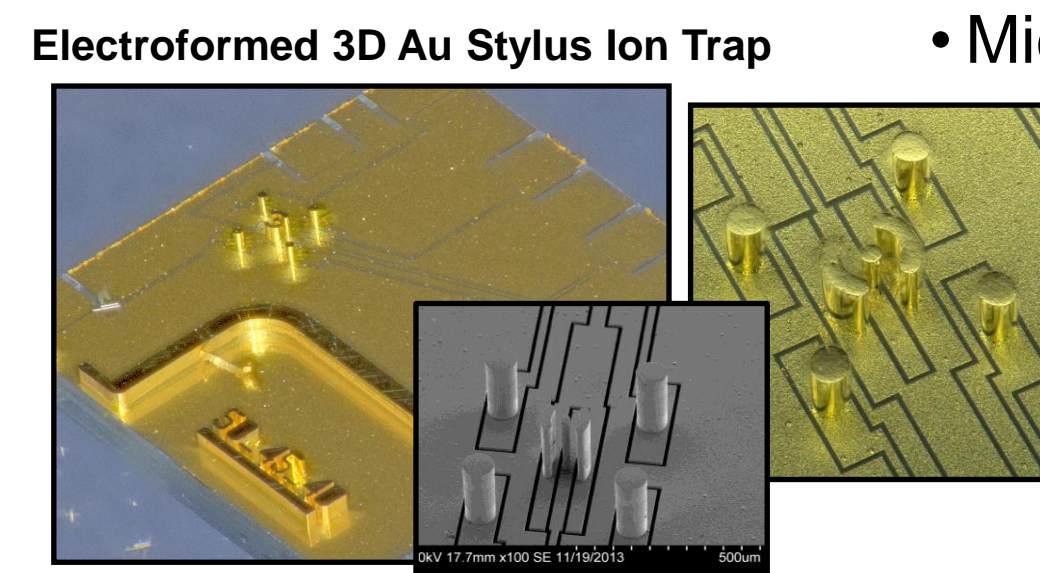


Metal Micromachining Team (MMT) Lithography Lab

- Hot Plate
- Wet Bench
- Resist Spinner
- Alignment Tool
- Vacuum Oven
- Microscopy



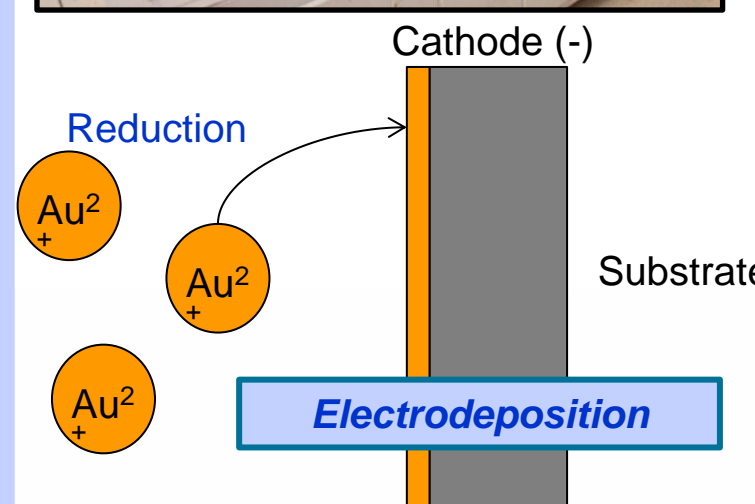
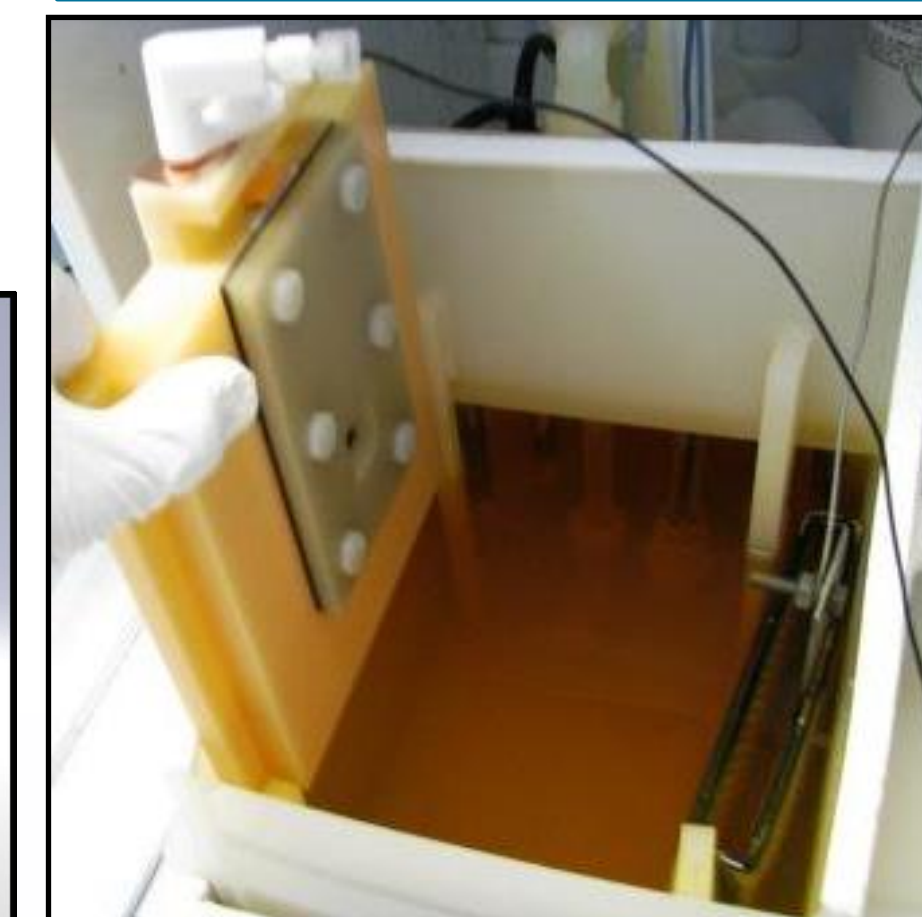
- LIGA
- Ultra thick PR techniques
- Class 100 cleanroom in house
- Access to Sandia Micro Fab Facility & MESA



MMT Electroplating/Electroforming Lab

- Hard Gold
- Soft Gold
- Nickel Sulfate
- Copper Sulfate
- Electroless Nickel
- Custom Solutions

MMT Adaptable Plating Tanks

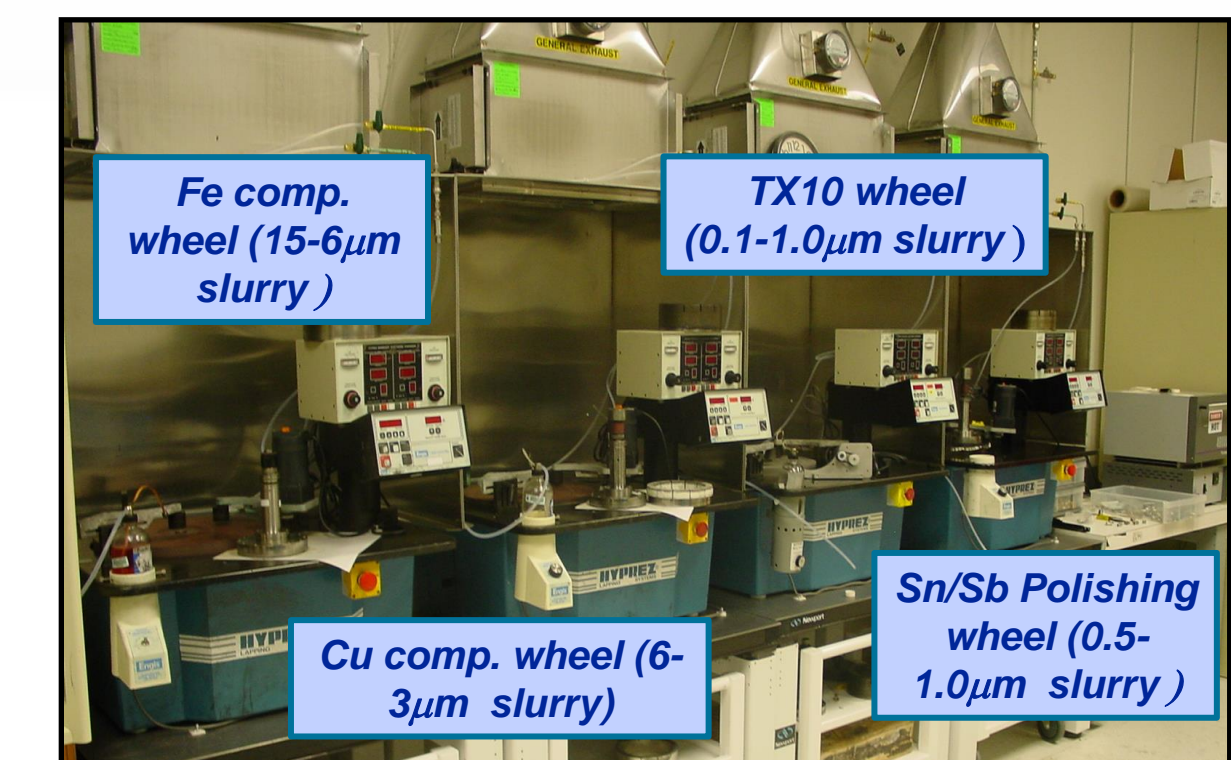


MMT Chemical Mechanical Planarization Lab

- Precision lapping, planarization and polishing capability
- Varying wheel composition to accommodate various material removal needs



- Controlled wafer, optics and device thinning
- Vacuum fixtures for 4 - 6 inch wafers
- Custom mounting fixtures to secure a multitude of devices

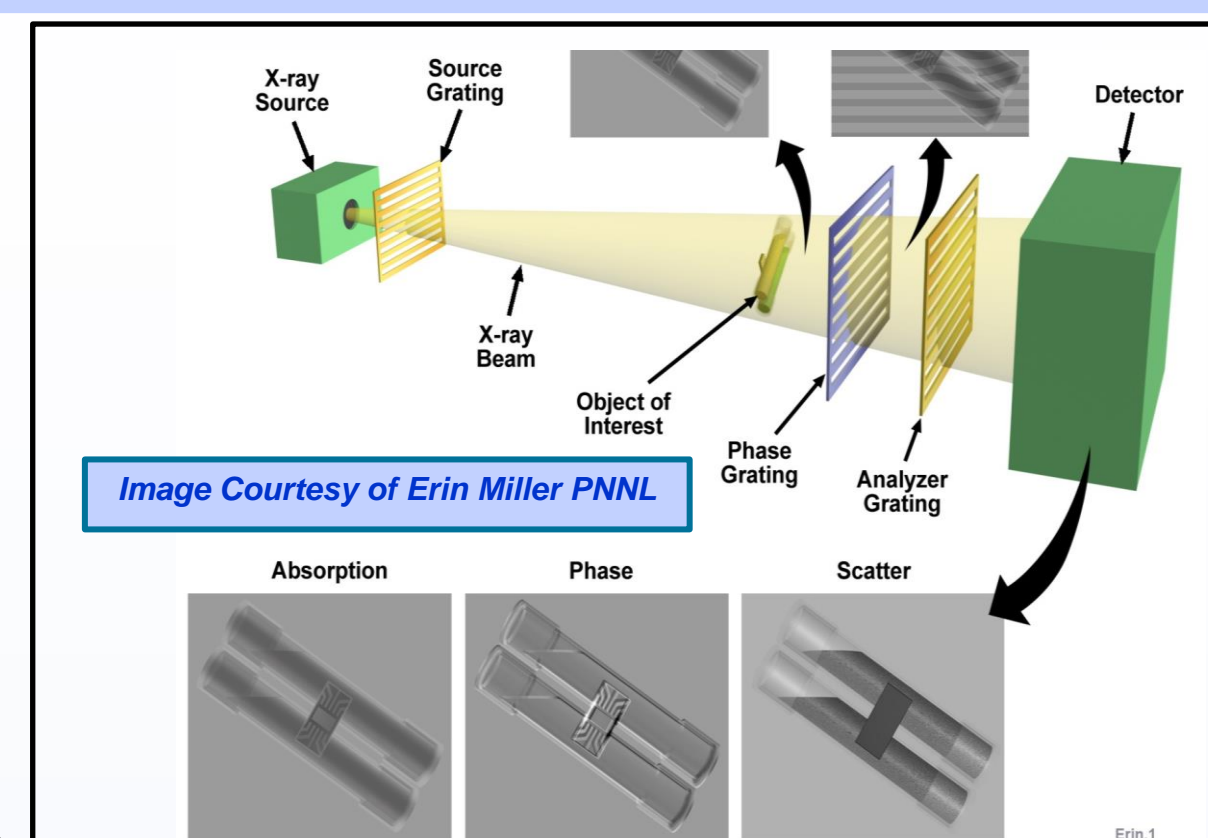


Au Formed Spiral Coil

MESA West 10kV 100um x120

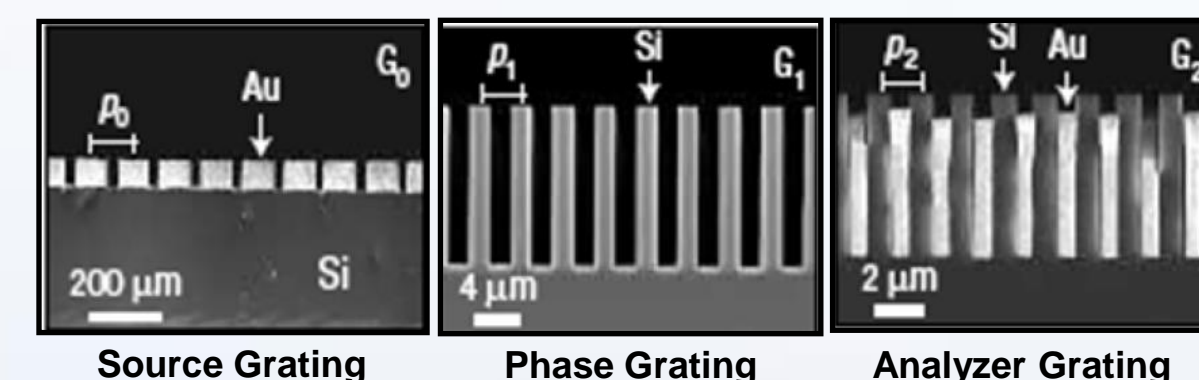
Enabling Technology for Phase Contrast Imaging

- Source Grating:** Enables use of conventional x-ray source in the lab
- Phase Grating:** Modulates the phase of the wavefront to form an interference pattern
- Analyzer Grating:** Converts the interference pattern of the x-rays to an intensity signal that can be recorded with a detector

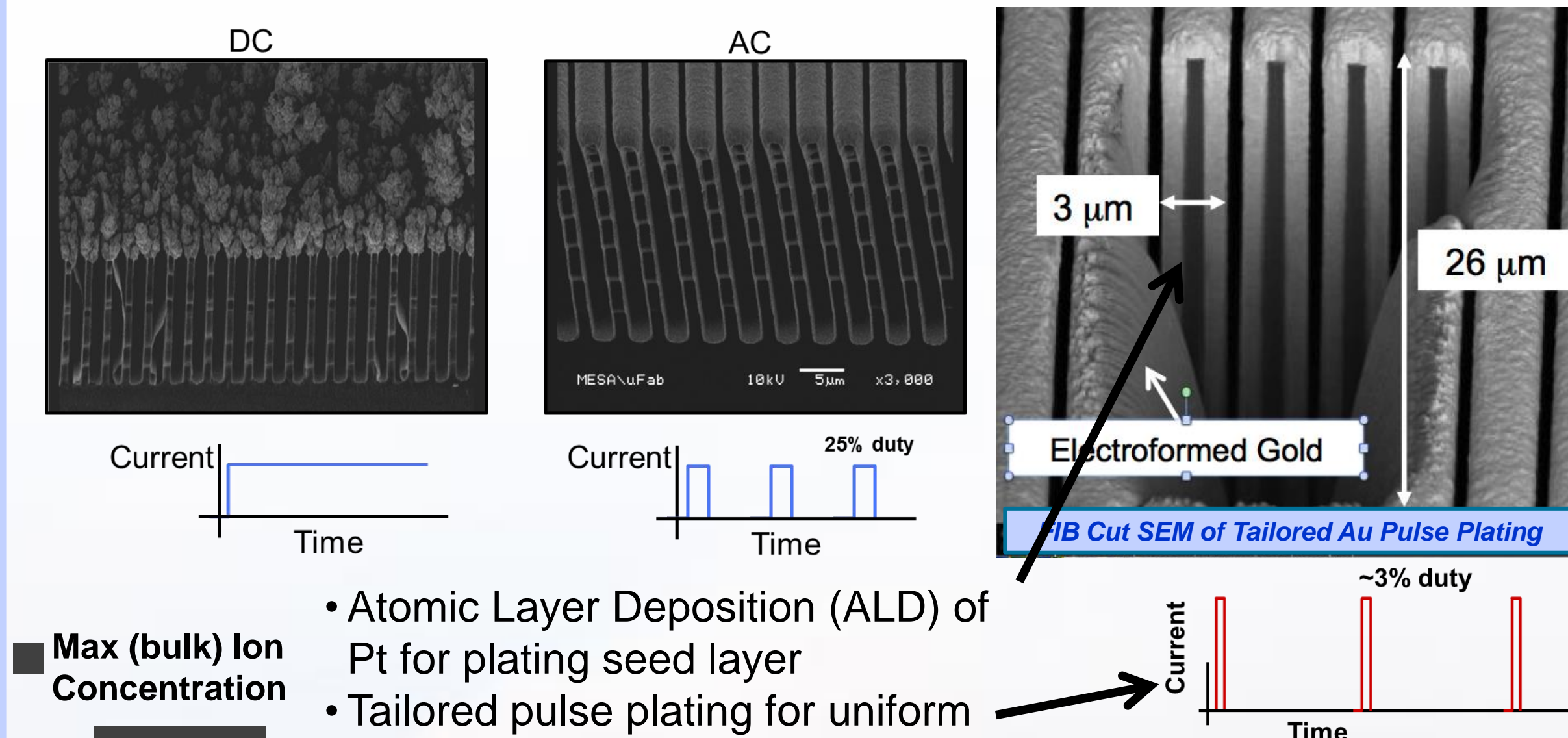


Benefits of XPCI

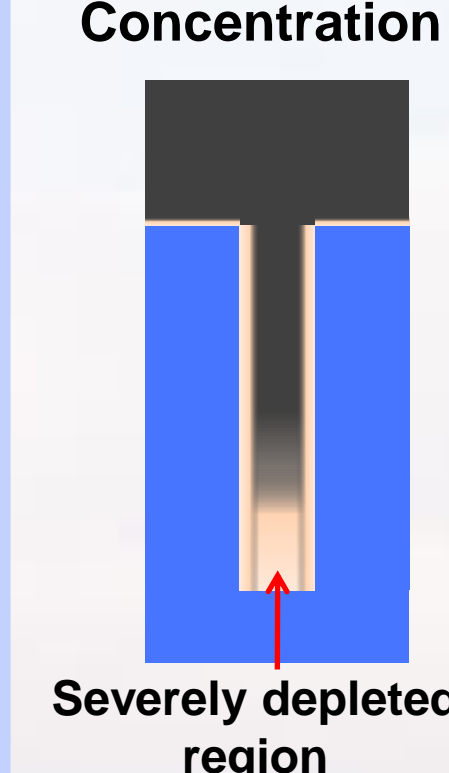
- No need for a synchrotron
- Higher resolution imaging than absorption based imaging
- Simplified optical arrangement
- Wide Area Imaging



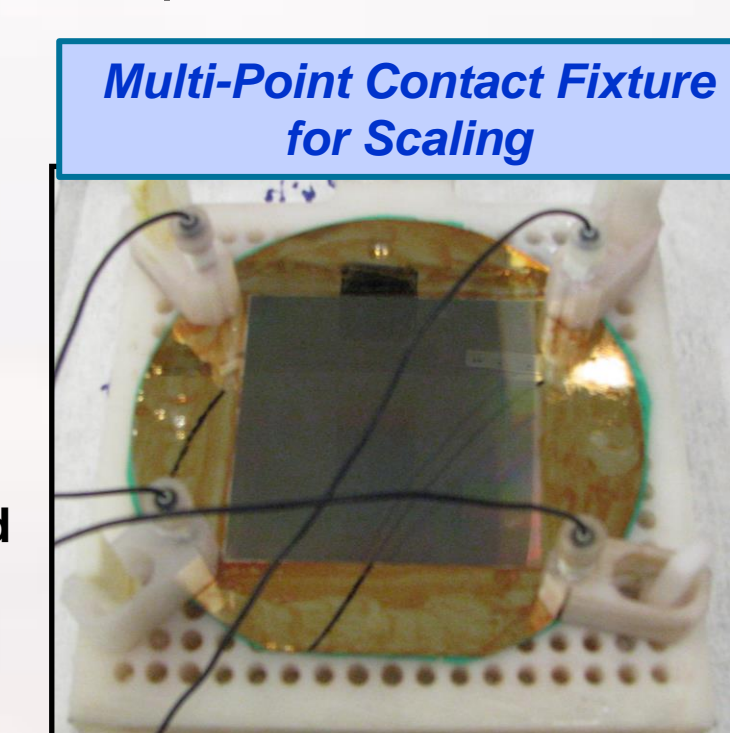
Optimization of the Au Electroplating Process



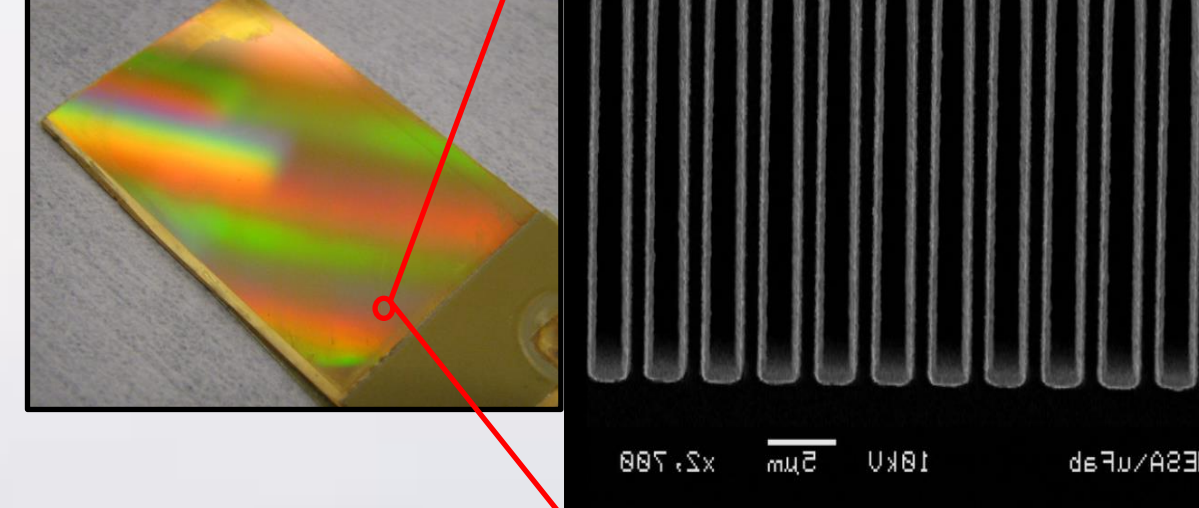
Max (bulk) Ion Concentration



- Atomic Layer Deposition (ALD) of Pt for plating seed layer
- Tailored pulse plating for uniform deposition



Coupon Size ~2cm² 50:1 Au Gratings



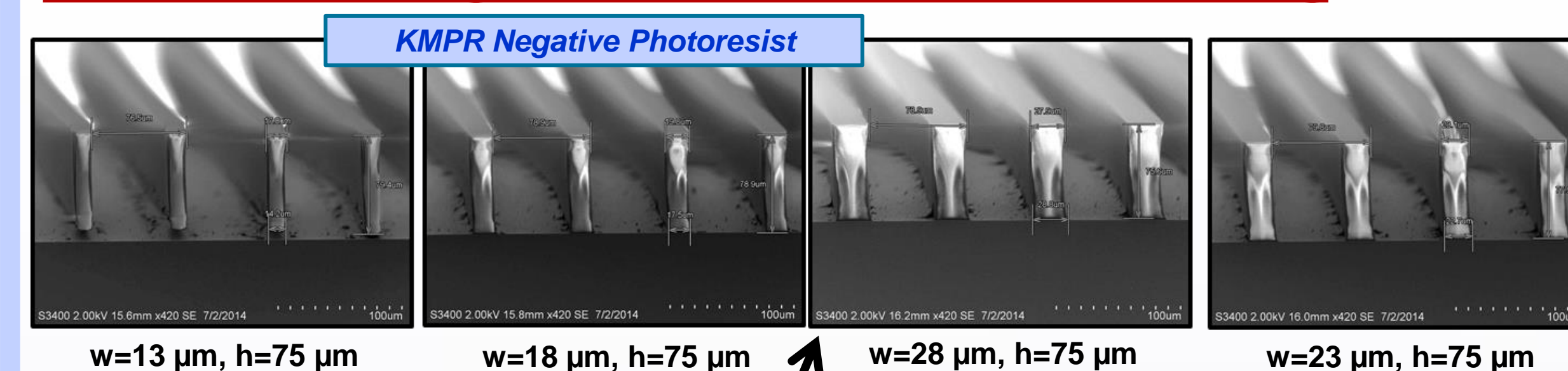
Full Wafer Gratings Plating

Realizing 16 in.² Grating Area

- Multiple electrical contacts
- Improved chemical flow
- Vibrating sample fixture
- Improved pulse plating regime

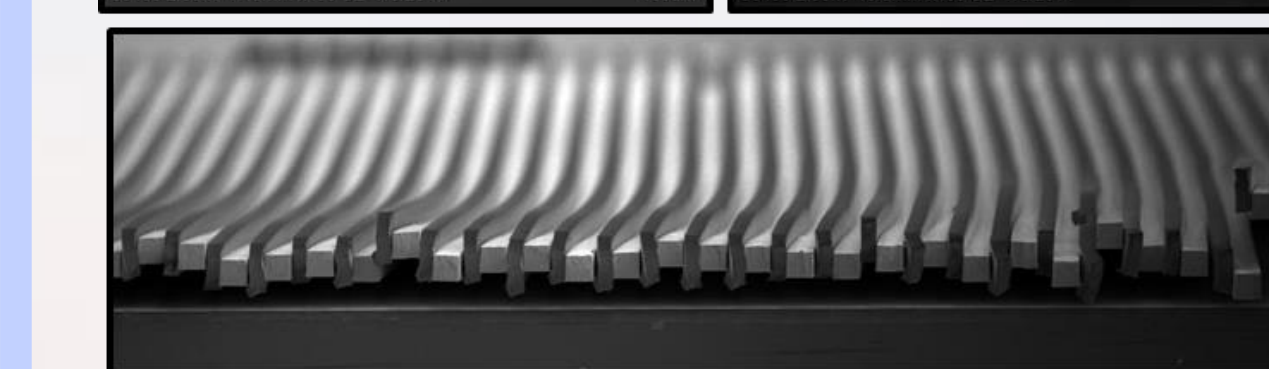
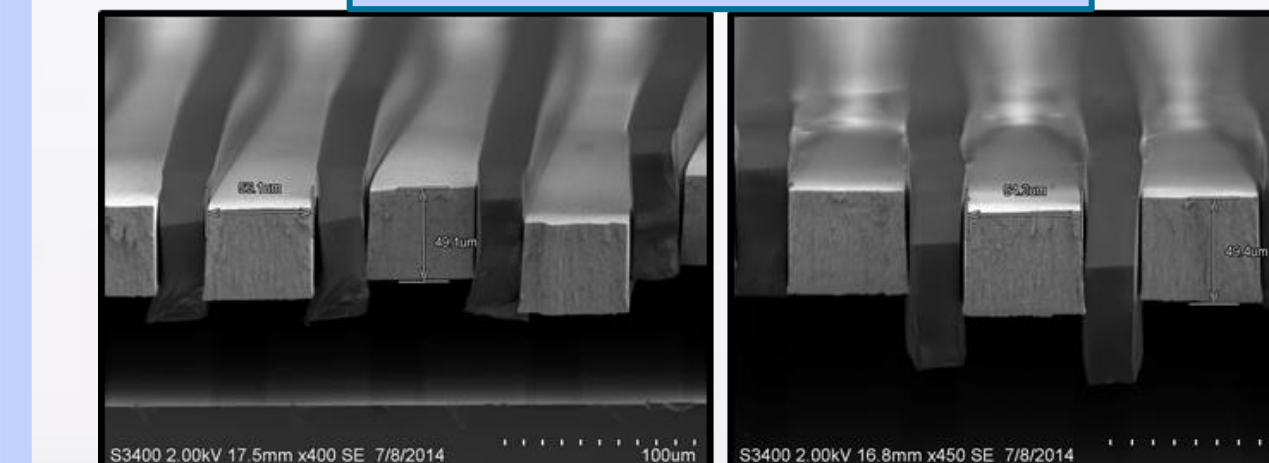
4 inch long 1 μ m wide Au gratings
100,000:1 Length:Width Ratio!

Au Source Gratings via UV Photoresist Trench Filling

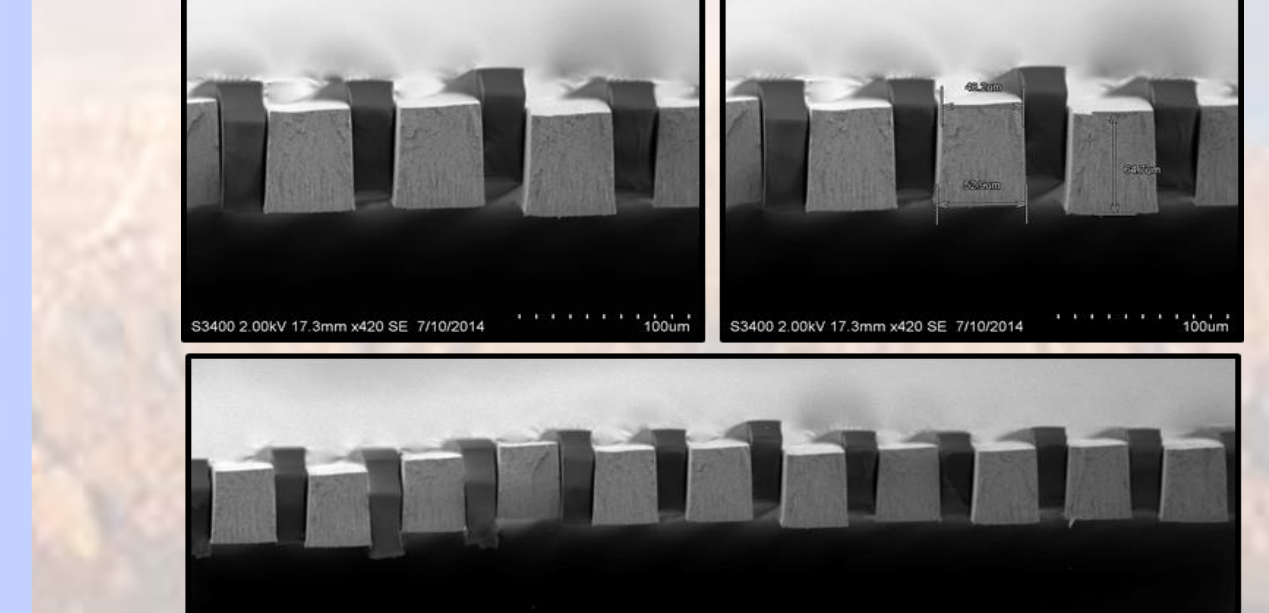


- KMPR produces straight sidewalls with sufficient structural stability
- Conventional positive resists result in insufficient sidewall profiles

50 μ m Thick Au Cross Section

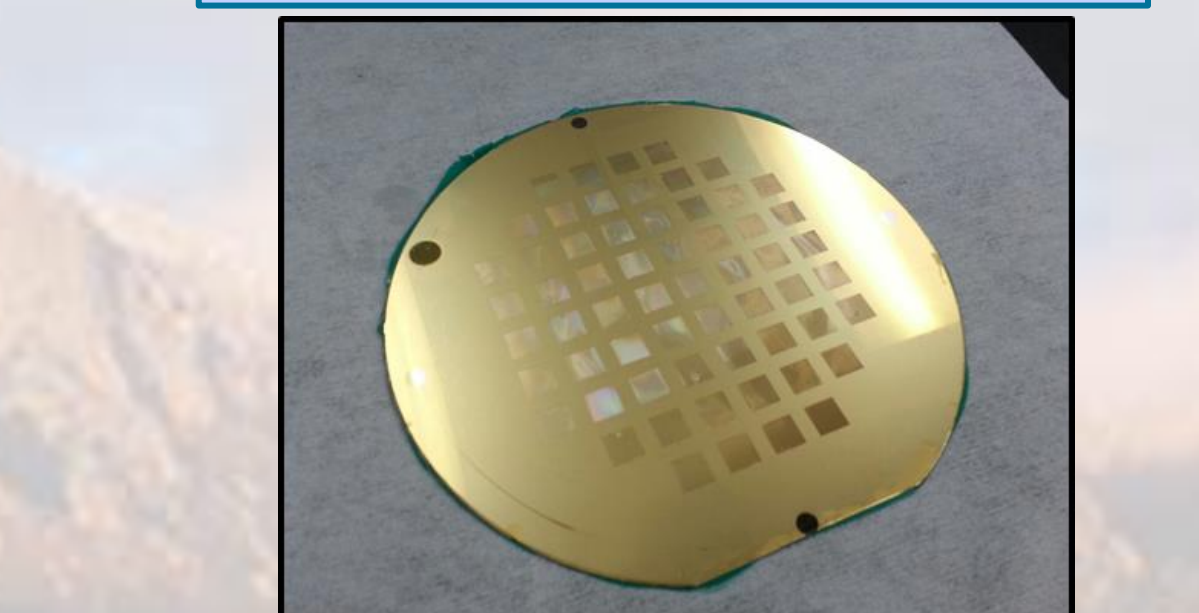


65 μ m Thick Au Cross Section



- Resist process is dependent on the "lifetime" of the wafer
- Lithography must be performed in a single day
- Plating must occur immediately after resist processing to prevent delamination and resist swelling

6 inch Wafer with Various Source Grating Sizes



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